

How to prove that a circuit is fault-free?

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan Proceedings : 15th Euromicro Conference on Digital System Design DSD 2012 : 5-8 September 2012, Cesme, Izmir, Turkey 2012 / p. 427-430 : ill
https://www.researchgate.net/publication/262271409_How_to_Prove_that_a_Circuit_is_Fault-Free

Multiple control fault testing in digital systems with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill
<http://dx.doi.org/10.1109/AQTR.2016.7501287>

Multiple fault testing in systems-on-chip with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Schölzel, Mario; Vierhaus, Heinrich Theodor Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 2015 / p. 66-71 : ill
<http://dx.doi.org/10.1109/IDT.2015.7396738>

Multiple stuck-at-fault detection theorem

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia 2012 / p. 236-241 : ill

Synthesis of multiple fault oriented test groups from single fault test sets [Electronic resource]

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2013 8th International Conference on Design & Technology of Integrated Systems in Nanoscale Era (DTIS) : 26-28 March 2013, Abu Dhabi, UAE 2013 / p. 36-41 : ill [CD-ROM]